Advanced Micro Devices

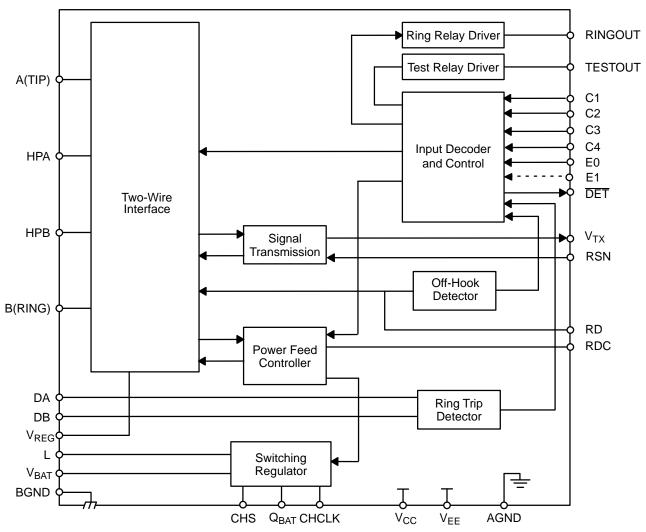
Am79533I/Am79534I

Subscriber Line Interface Circuit

DISTINCTIVE CHARACTERISTICS

- Programmable constant current feed
- Programmable loop detect threshold
- Performs polarity reversal
- Tip open state for ground start lines
- Line feed characteristics independent of battery variations
- On-chip switching regulator for low power dissipation
- Two-wire impedance set by single external impedance
- On-hook transmission

BLOCK DIAGRAM

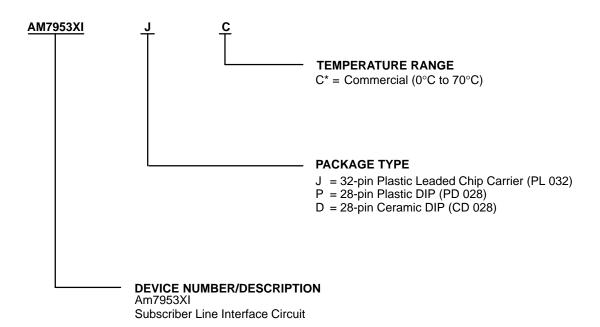




ORDERING INFORMATION

Standard Products

AMD[®] standard products are available in several packages and operating ranges. The order number (Valid Combination) is formed by a combination of the elements below.



Valid Combinations					
AM7953XI	DC, JC, PC				

Valid Combinations

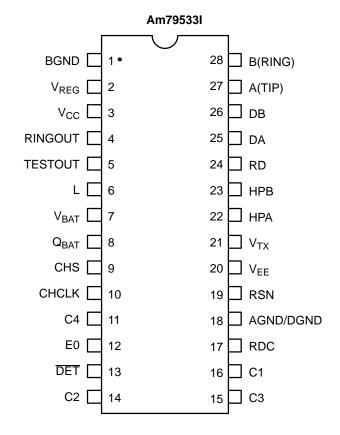
Valid Combinations list configurations planned to be supported in volume for this device. Consult the local AMD sales office to confirm availability of specific valid combinations, to check on newly released combinations, and to obtain additional data on AMD's standard military grade products.

Note:

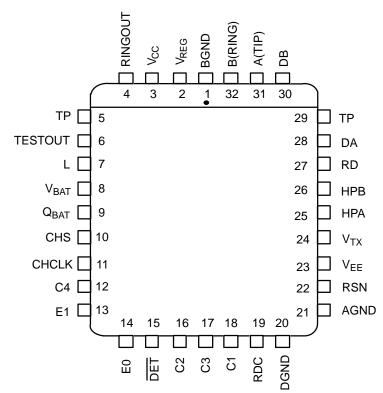
* Specifications in this data sheet are guaranteed by testing from 0°C to +70°C. Performance from –40°C to +85°C is guaranteed by characterization and periodic sampling of production units..

CONNECTION DIAGRAM

Top View



Am79534I



Note:

Pin 1 is marked for orientation.



PIN DESCRIPTION

AGND/DGND

(Ground)

Analog and Digital ground.

Note: Analog and digital ground are connected internally to a single pin.

A(TIP)

(Output)

Output of A(TIP) power amplifier.

BGND

(Ground)

Battery (power) ground.

B(RING)

(Output)

Output of B(RING) power amplifier.

C3-C1

Decoder (Inputs)

TTL compatible. C3 is MSB and C1 is LSB.

C4

Test Relay Driver Command (Input)

TTL compatible. A logic High enables the driver.

CHCLK

Chopper Clock (Input)

Input to switching regulator (TTL compatible). Frequency = 256 kHz (Nominal).

CHS

Chopper Stabilization (Input)

Connection for external stabilization components.

DA

Ring Trip Negative (Input)

Negative input to ring trip comparator.

DB

Ring Trip Positive (Input)

Positive input to ring trip comparator.

DET

Detector (Output)

When enabled, a logic Low indicates that the selected detector is tripped. The detector is selected by the logic inputs (C3–C1, E0, and E1). The output is open-collector with a built-in pull-up resistor.

E0

Read Enable (Input)

A logic High enables DET. A logic Low disables DET.

E1

Ground Key Enable (Input)

When E0 is High, E1 = High connects the ground-key detector to \overline{DET} , and E1 = Low connects the off-hook or ring trip detector to \overline{DET} .

HPA

A(TIP) side of high-pass filter capacitor.

HPB

B(RING) side of high-pass filter capacitor.

L

Switching Regulator Power Transistor (Output)

Connection point for filter inductor and anode of catch diode. This pin will have up to 60 volts of pulse waveform on it and must be isolated from sensitive circuits. Extreme care must be taken to keep the diode connections short because of the high currents and high di/dt.

Q_{BAT}

Quiet Battery

Filtered battery supply for the signal processing circuits.

RD

Detect Resistor Pin

Threshold modification and filter point for the off-hook detector.

RDC

DC Feed Resistor Pin

Connection point for the DC feed current programming network. The other end of the network connects to the receiver summing node (RSN). The sign of V_{RDC} is minus for normal polarity and plus for reverse polarity. The magnitude is typically 2.5 V.

RINGOUT

Ring Relay Driver (Output)

Sourcing from V_{CC} with internal diode to Q_{BAT}

RSN

Receive Summing Node (Input)

The metallic current (both AC and DC) between A(TIP) and B(RING) is equal to 1000 times the current into this pin. The networks that program receive gain, two-wire impedance, and feed current all connect to this node.

FINAL



TESTOUT

Test Relay Driver (Output)

Sourcing from V_{CC} with internal diode to Q_{BAT}.

V_{BAT}

Battery supply.

V_{CC}

+5-V power supply.

VEE

-5-V power supply.

V_{REG}

Regulated Voltage (Input)

Provides negative power supply for power amplifiers, connection point for inductor, filter capacitor and chopper stabilization.

V_{TX}

Transmit Audio (Output)

This output is a unity gain version of the A(TIP) and B(RING) metallic voltage. The other end of the two-wire input impedance programming network connects here.



ABSOLUTE MAXIMUM RATINGS

Storage Temperature –55°C to +150°C

Storage remperature 60 6 to 1766 6
Ambient temperature, operating 0°C to +70°C
V_{CC} with respect to AGND/DGND $-0.4~V$ to +7 V
V_{EE} with respect to AGND/DGND +0.4 V to -7 V
V_{BAT} with respect to AGND/DGND +0.4 V to -70 V
AGND/DGND with respect to BGND +1 V to -3 V
A(TIP) or B(RING) to BGND:
Continuous
10 ms (F = 0.1 Hz) -70 V to +5 V
1 μs (F = 0.1 Hz)90 V to +10 V
250 ns (F = 0.1 Hz) -120 V to +15 V
Current from A(TIP) or B(RING)±150 mA
Voltage on RINGOUT V_{BAT} to V_{CC}
Voltage on TESTOUT V_{BAT} to V_{CC}
Current through relay drivers or internal driver catch diodes 60 mA
Voltage on ring trip inputs DA and DB V _{BAT} to 0 V
Current into ring trip inputs±10 mA
Peak current into regulator switch (L pin) 150 mA
Switcher transient peak off voltage on L pin +1.0 V
Voltage on chopper stabilization pin CHS
C1, C2, C3, C4, E0, E1, CHCLK, to AGND/DGND0.4 V to V _{CC} +0.4 V
Maximum power dissipation, T _A = 70°C (See note):
In 28-pin ceramic DIP
In 28-pin plastic DIP 1.0 W

Note: Thermal limiting circuitry on chip will shut down the circuit at a junction temperature of about 165°C. The device should never be exposed to this temperature. Operation above 145°C junction temperature may degrade device reliability. See SLIC Packaging Considerations section for more information.

Stresses above those listed under Absolute Maximum Ratings may cause permanent device failure. Functionality at or above these limits is not implied. Exposure to Absolute Maximum Ratings for extended periods may affect device reliability.

OPERATING RANGES

Commercial (C) Devices

Ambient Temperature 0°C to +70°C*
V_{CC} 4.75 V to 5.25 V
$V_{\mbox{\footnotesize EE}}$
$V_{BAT} \dots -40.5 \ V$ to –58 V
AGND0 V
BGND with respect to
AGND/DGND100 mV to +100 mV
Load resistance on V_{TX} to ground $\ldots10\;k\Omega$ minimum

Operating Ranges define those limits between which the functionality of the device is guaranteed.

^{*} Specifications in this data sheet are guaranteed by testing from 0°C to +70°C. Performance from -40°C to +85°C is guaranteed by characterization and periodic sampling of production units.



ELECTRICAL CHARACTERISTICS (See Note 1)

		Final				
Description	Test Conditions	Min	Тур	Max	Unit	Note
Analog (V _{TX}) output impedance			3		Ω	
Analog (V _{TX}) output offset	0°C to +70°C -40°C to +85°C	-35 -40		+35 +40	mV	5
Analog (RSN) input impedance	300 Hz to 3.4 kHz		1	20	Ω	
Longitudinal impedance at A or B	300 FIZ 10 3.4 KHZ			35	22	
Overload level	4-wire	-2.2		+2.2	Vpk	2
$Z_{2WIN} = 600 \Omega$ to 900Ω	2-wire	-2.2		+2.2		
Transmission Performance, 2-Wire	e Impedance					
Two-wire return loss	300 Hz to 500 Hz	26				
(See Test Circuit D)	500 Hz to 2500 Hz	26			dB	5
	2500 Hz to 3400 Hz	20				
Longitudinal Balance (2-Wire and	4-Wire, See Test Circuit C)					
Longitudinal to metallic L-T, L-4						
$R_L = 600 \Omega$	300 Hz to 3400 Hz	48			dB	
Longitudinal signal generation 4-L	300 Hz to 800 Hz	40			dB	
Longitudinal current capability	Active state		25		mArms	
per wire	OHT state		18		1	
Insertion Loss (2-Wire to 4-Wire a	nd 4-Wire to 2-Wire, See Test Circ	cuits A and	B)		•	
Gain accuracy	0 dBm, 1 kHz 0°C to +70°C 0 dBm, 1 kHz -40°C to +85°C	-0.15 -0.20		+0.15 +0.20	dB dB	5
Variation with frequency	300 Hz to 3400 Hz Relative to 1 kHz 0°C to +70°C -40°C to +85°C	-0.1 -0.15		+0.1 +0.15	dB dB	5
Gain tracking	+7 dBm to -55 dBm -4 dBm Reference 0°C to +70°C -40°C to +85°C	-0.1 -0.15		+0.1 +0.15	dB dB	5 5
Balance Return Signal (4-Wire to 4	I-Wire, See Test Circuit B)					
Gain accuracy	0 dBm, 1 kHz 0°C to +70°C 0 dBm, 1 kHz -40°C to +85°C	-0.15 -0.20		+0.15 +0.20	dB dB	5
Variation with frequency	300 Hz to 3400 Hz Relative to 1 kHz 0°C to +70°C -40°C to +85°C	-0.1 -0.15		+0.1 +0.15	dB dB	5
Gain tracking	+7 dBm to -55 dBm -4 dBm Reference 0°C to +70°C -40°C to +85°C	-0.1 -0.15		+0.1 +0.15	dB dB	5
Group delay	F = 1 kHz		5.3		μs	
Total Harmonic Distortion (2-Wire	to 4-Wire or 4-Wire to 2-Wire, Se	e Test Circ	uits A an	d B)	_	•
Total harmonic distortion	0 dBm, 300 Hz to 3400 Hz +6 dBm, 300 Hz to 3400 Hz		-64 -55	-50 -40	dB dB	
					-	



ELECTRICAL CHARACTERISTICS (continued)

			Final			
Description	Test Conditions	Min	Тур	Max	Unit	Note
Idle Channel Noise	•	•	•	•	_	•
C-message	2-wire			+15	-ID	5, 7
weighted noise	4-wire			+15	dBrnc	5, 7
Psophometric	2-wire			-75	al Duna in	
weighted noise	4-wire			-75	d Bmp	
Single Frequency Out-of-Band	Noise (See Test Circuit E)	•	•	•	•	•
Metallic	4 kHz to 9 kHz 9 kHz to 1 MHz		-76 -76		dBm	4, 5, 8 4, 5, 8
	256 kHz and harmonics		-57		dBm	4,5
Longitudinal	1 kHz to 15 kHz Above 15 kHz		-70 -85		dBm	4, 5, 8 4, 5, 8
	256 kHz and harmonics		-57		dBm	4, 5
DC Feed Currents (See Figure 1	I) V _{BAT} = -48 V		•		-	•
Active mode loop current accuracy	I_{LOOP} (nominal) = 33 mA, R _L = 600 Ω	-8		+8	%	
Active mode loop current	R _L = 1240 Ω	30			mA	
OHT mode	$R_L = 600 \Omega$	14.5	16.5	18.5		
Tip open mode	$R_L = 600 \Omega$			1.0	mA	Ī
Disconnect mode	$R_L = 0 \Omega$			1.0	1	
Power Dissipation V _{BAT} = -48 V		•	•	•		•
On-hook open circuit			40	120		
On-hook OHT mode			150	250	1	
On-hook active mode			210	400	mW	
Off-hook OHT mode	$R_L = 600 \Omega$		400	750	1	
Off-hook active mode	$R_L = 600 \Omega$		550	1000	1	
Supply Current						
V _{CC} On-hook supply current	Open circuit mode		3	4.5		
	OHT mode		6	10	1	
	Active mode		7.5	12	1	
V _{EE} On-hook supply current	Open circuit mode		1.0	2.3	1	
	OHT mode		2.2	3.5	mA	
	Active mode		2.7	6.0	1	
V _{BAT} On-hook supply current	Open circuit mode		0.4	1.0	1	
	OHT mode		3.0	5.0		
	Active mode		4.0	6.0	1	



ELECTRICAL CHARACTERISTICS (continued)

		Final				1
Description	Test Conditions	Min	Тур	Max	Unit	Note
Power Supply Rejection	Ratio (Vripple = 50 mVrms)			•		
V _{CC}	40 Hz to 3400 Hz	20	35			
	3.4 kHz to 50 kHz	20	30			
V _{EE}	40 Hz to 3400 Hz	20	30		-10	0.7
	3.4 kHz to 50 kHz	15	25		dBm	6, 7
V _{BAT}	40 Hz to 3400 Hz	27	30		1	
	3.4 kHz to 50 kHz	20	30		1	
Off-Hook Detector				<u> </u>	•	
Current threshold	I _{DET} = 365 / R _D ; I _{DET} = 7.14 mA	-20		+20	%	
Ring Trip Detector Input	s	•		•		•
Bias current		-25	4		μΑ	
Offset voltage	Source resistance = 0 to 200K	-50	0	+50	mV	
Logic Inputs (C1, C2, C3	s, C4, E0, E1, and CHCLK)			•		
Input High voltage		2.0			V	
Input Low voltage				0.8		
Input High current	All inputs except E1	- 75		40	μΑ	
Input High current	Input E1	– 75		45	μΑ	
Input Low current		-0.4	-0.2		mA	
Logic Output (DET)	-	-	-	-	-	-
Output Low voltage	I _{OUT} = 0.8 mA			0.4	V	
Output High voltage	I _{OUT} = -0.1 mA	2.4				

Table 1. SLIC Decoding

		DET Ou	utput	
State	C3 C2 C1	Two-Wire Status	E0 = 1 E1 = 0	E0 = 1 E1 = 1
0	0 0 0	Open circuit	Ring trip	Ring trip
1	0 0 1	Ringing	Ring trip	Ring trip
2	0 1 0	Active	Loop det.	Ground key
3	0 1 1	On-hook TX (OHT)	Loop det.	Ground key
4	1 0 0	Tip open	Loop det.	_
5	1 0 1	Reserved	Loop det.	_
6	1 1 0	Active polarity reversal	Loop det.	Ground key
7	1 1 1	OHT polarity reversal	Loop det.	Ground key

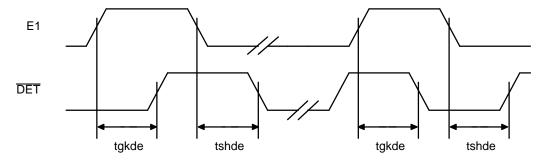


SWITCHING CHARACTERISTICS Am79533I/Am79534I

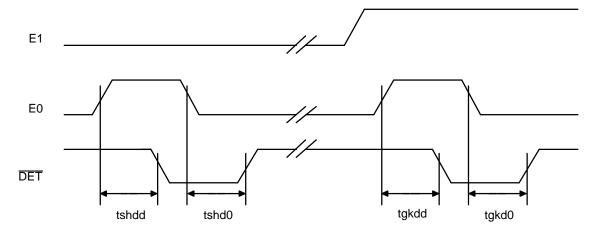
Symbol	Parameter	Test Conditions	Temperature Range	Min	Тур	Max	Unit	Note
taleda	E1 Low to DET High (E0 = 1)		0°C to +70°C -40°C to +85°C			3.8 4.0		5 5
tgkde	E1 Low to DET Low (E0 = 1)	Ground key detect mode	0°C to +70°C -40°C to +85°C			1.1 1.6	μs	5 5
tgkdd	E0 High to DET Low (E1 = 0)	R _L open, R _G connected (See Figure H)	0°C to +70°C -40°C to +85°C			1.1 1.6		5 5
tgkd0	E0 Low to DET High (E1 = 0)		0°C to +70°C -40°C to +85°C			3.8 4.0		5 5
	E1 High to DET Low (E0 = 1)		0°C to +70°C -40°C to +85°C			1.2 1.7		5 5
tshde	E1 High to DET High (E0 = 1)	Outtob hash data to an da	0°C to +70°C -40°C to +85°C			3.8 4.0	μs	5 5
tshdd	E0 High to DET Low (E1 = 1)	Switch hook detect mode $R_L = 600 \Omega$, R_G open (See Figure G)	0°C to +70°C -40°C to +85°C			1.1 1.6		5 5
tshd0	E0 Low to DET High (E1 = 1)		0°C to +70°C -40°C to +85°C			3.8 4.0		5 5

SWITCHING WAVEFORMS Am79533I/Am79534I

E1 to DET



E0 to DET

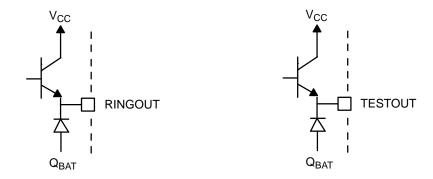


Note:

All delays measured at 1.4-V level.

11701B-002

RELAY DRIVER SPECIFICATIONS



Description	Test Conditions	Min	Тур	Max	Unit	Note
Relay Driver Outputs (RINGOU	T, TESTOUT)					
On voltage	50-mA source	V _{CC} -2			V	
Off leakage			0.5	100	μΑ	
Clamp voltage	50-mA sink	Q _{BAT} –2	Q _{BAT} –1.3		V	

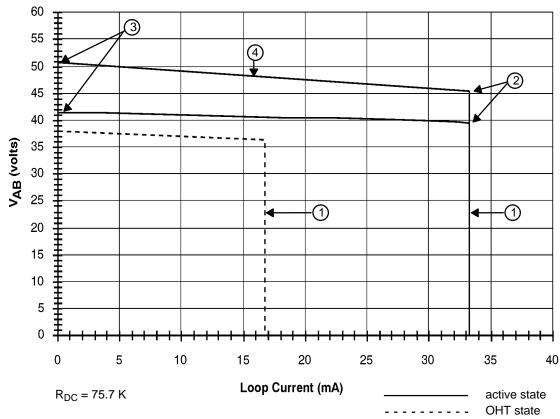
Notes:

- 1. Unless otherwise noted, test conditions are: $V_{BAT} = -48 \text{ V}$, $V_{CC} = +5 \text{ V}$, $V_{EE} = -5 \text{ V}$, $R_{L} = 600 \Omega$, $C_{HP} = 0.22 \,\mu\text{F}$, $R_{DC1} = 37.4 \text{ K}$, $R_{DC2} = 38.3 \text{ K}$, $C_{DC} = 0.1 \,\mu\text{F}$, $R_{d} = 51.1 \text{ K}$, No fuse resistors, Two-Wire AC output impedance programming impedance (Z_{T}) = 600K resistive, Receive input summing impedance (Z_{RX}) = 300 K resistive. (See Table 1 for component formulas.)
- 2. Overload level is defined when THD = 1%.
- 3. Balance return signal is the signal generated at V_{TX} by V_{RX} . This spec assumes that the two-wire AC load impedance matches the impedance programmed by Z_T .
- 4. These tests are performed with a longitudinal impedance of 90Ω and metallic impedance of 300Ω for frequencies below 12 kHz and 135 Ω for frequencies greater than 12 kHz. These tests are extremely sensitive to circuit board layout. Please refer to application notes for details.
- 5. Not tested in production. This parameter is guaranteed by characterization or correlation to other tests.
- 6. This parameter is tested at 1 kHz in production. Performance at other frequencies is guaranteed by characterization.
- 7. When the SLIC is in the Anti-sat 2 operating region, this parameter will be degraded. The exact degradation will depend on system design. The Anti-sat 2 region occurs at high loop resistances when $|V_{BAT}| |V_{AX} V_{BX}|$ is less than approximately 15 V.
- 8. Fundamental and harmonics from 256-kHz switch regulator chopper are not included.



Table 2. User-Programmable Components

$Z_T = 1000 (Z_{2WIN} - 2R_F)$	Where Z_T is connected between the V_{TX} and RSN pins. The fuse resistors are R_F and Z_{2WIN} is the desired 2-wire AC input impedance. When computing Z_T , any external stray capacitance between V_{TX} and RSN must be taken into account.
$Z_{RX} = \frac{1}{2Z_{T}}$	Where Z_{RX} is connected from V_{RX} to the RSN pin, Z_T is defined above. This equation sets the receive gain to 0 dB when the SLIC is terminated with an impedance equal to Z_{2WIN} .
$R_{DC1} + R_{DC2} = \frac{2500}{I_{FEED}}$	Where R_{DC1} , R_{DC2} , and C_{DC} form the network connected to the RDC pin. R_{DC1} and R_{DC2} are approximately equal.
$C_{\rm DC} = 1.5 \text{ ms} \bullet \frac{R_{\rm DC1} + R_{\rm DC2}}{R_{\rm DC1} \bullet R_{\rm DC2}}$	
$R_{\rm D} = \frac{365}{I_{\rm T}}, C_{\rm D} = \frac{0.5 \text{ ms}}{R_{\rm D}}$	Where R_D and C_D form the network connected from RD to $-5~\rm V$ and I_T is the threshold current between on-hook and off-hook.



Notes:

1. Constant current region:

active state,
$$I_L = \frac{2500}{R_{DC}}$$

OHT state,
$$I_L = \frac{1}{2} \bullet \frac{2500}{R_{DC}}$$

2. Anti-sat cut-in:

$$V_{AB} = 1.067 |V_{BAT}| - 13.57,$$

$$|V_{BAT}| \le 55.7~V$$

$$V_{AB} = 45.81 V$$
,

$$|V_{BAT}| > 55.7 V$$

3. Open-circuit voltage (active state):

$$V_{AB} = 1.067 \; |V_{BAT}| - 11.78,$$

$$|V_{BAT}| \le 58.9 \ V$$

$$V_{AB}=51.1~V,$$

$$|V_{BAT}| > 58.9 V$$

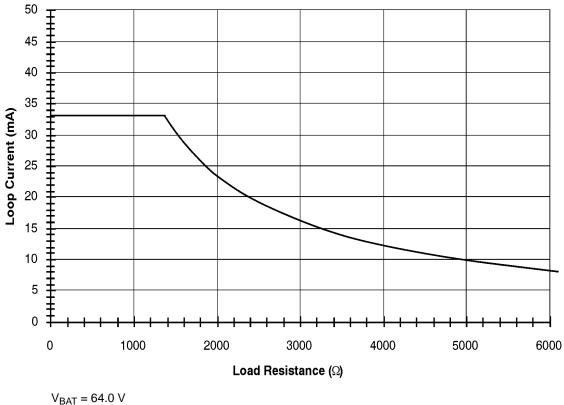
4. Anti-sat -1 region:

$$V_{AB} = 51.1 - I_L \frac{R_{DC}}{470.4}$$

Anti-sat -2 region:

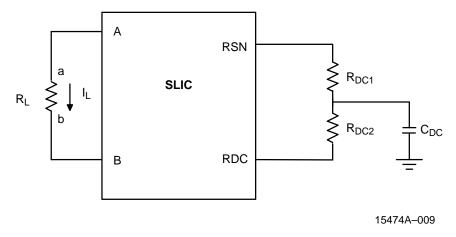
$$V_{AB} = 1.067 |V_{BAT}| - 11.78 - I_L \frac{R_{DC}}{1385}$$

a. V_A-V_B (V_{AB}) Voltage vs Loop Current (Typical)



 $R_{DC} = 75.7 \text{ K}$

b. Loop Current vs Load Resistance (Typical)



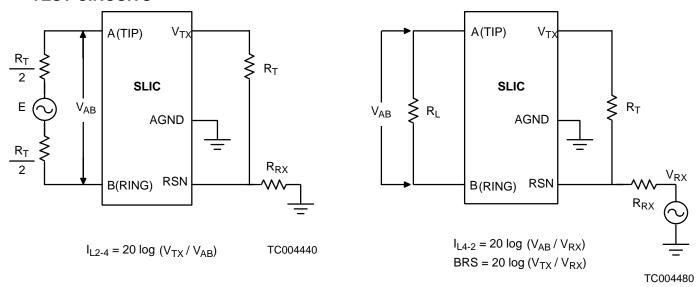
c. Feed Programming

Note:

Current programmed by R_{DC1} and R_{DC2} .

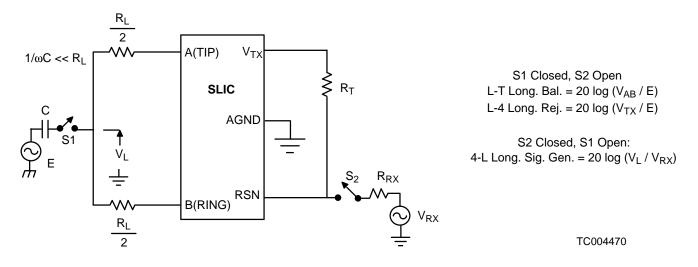
Figure 1. DC Feed Characteristics

TEST CIRCUITS

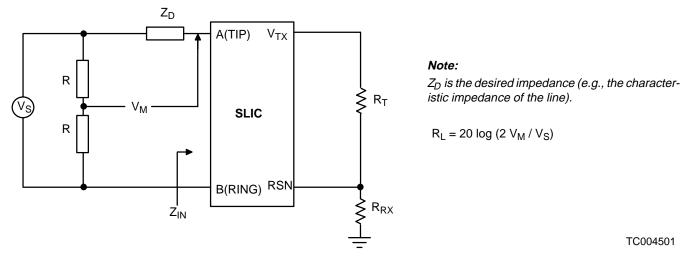


A. Two-to-Four-Wire Insertion Loss

B. Four-to-Two-Wire Insertion Loss and Balance Return Signal

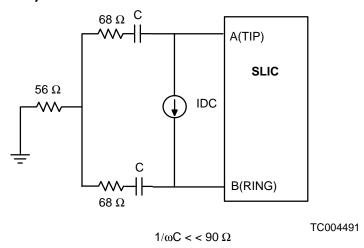


C. Longitudinal Balance (IEEE)

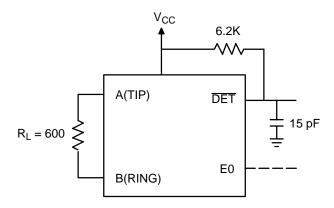


D. Two-Wire Return Loss Test Circuit

TEST CIRCUITS (continued)



E. Single Frequency Noise



F. Loop Detect Switching